

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/670,377	09/26/2003	Makoto Haseyama	990675B	6906
38834 75	590 08/18/2004		EXAMINER	
WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP			CHAN, EMILY Y	
1250 CONNECTICUT AVENUE, NW SUITE 700		ART UNIT	PAPER NUMBER	
WASHINGTON, DC 20036			2829	
			DATE MAILED: 08/18/2004	L

Please find below and/or attached an Office communication concerning this application or proceeding.

Q1

	Application No.	Applicant(s)			
	10/670,377	HASEYAMA ET AL.			
Office Action Summary	Examiner	Art Unit			
	Emily Y Chan	2829			
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address			
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	66(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days fill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	s will be considered timely. the mailing date of this communication. O (35 U.S.C. § 133).			
Status					
 Responsive to communication(s) filed on <u>26 September 2003</u>. This action is FINAL. 2b) This action is non-final. Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i>, 1935 C.D. 11, 453 O.G. 213. 					
Disposition of Claims		,			
 4) ☐ Claim(s) 20 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or 					
Application Papers					
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) accomplished any not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine	epted or b) objected to by the lideration of the drawing (s) is objected in the drawing (s) is objected in the lideration of the lideratio	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 09/333,984. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s)					
Notice of References Cited (PTO-892) Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal F 6) Other:	•			

Application/Control Number: 10/670,377

Art Unit: 2829

DETAILED ACTION

Claims 1-19 are cancelled

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in a patent granted on an application for patent by another filed in the United States before the invention thereof by the applicant for patent, or on an international application by another who has fulfilled the requirements of paragraphs (1), (2), and (4) of section 371(c) of this title before the invention thereof by the applicant for patent.

The changes made to 35 U.S.C. 102(e) by the American Inventors Protection Act of 1999 (AIPA) and the Intellectual Property and High Technology Technical Amendments Act of 2002 do not apply when the reference is a U.S. patent resulting directly or indirectly from an international application filed before November 29, 2000. Therefore, the prior art date of the reference is determined under 35 U.S.C. 102(e) prior to the amendment by the AIPA (pre-AIPA 35 U.S.C. 102(e)).

1. Claim 20 is rejected under 35 U.S.C. 102(e) as being anticipated by Kasukabe et al ('863).

Kasukabe et al ('863) (see Fig. 12 and Col. 20, lines 64-65) disclose a method of testing a device, comprising the step of:

electrically connecting electrode pads (117a and see Col. 21, lines 14-20) of a device testing contactor (probing device 110) to electrodes (3) of a device being tested (2);

Application/Control Number: 10/670,377

Art Unit: 2829

the electrode pads (117a) being formed on a wiring board (117) of the device testing contactor (probing device 110), and being reinforced by a reinforcing member (110d), and

the device testing contactor (probing device 110) comprising the wiring board (117) and the reinforcing member (110d) collectively bonded to each other.

2. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Yamaguchi Hidenobu (JP 829751) discloses a semiconductor device inspecting handler comprising electrode pads of a device testing contactor electrically connecting to electrodes of a device being tested and a reinforcing member being fixed to a base substrate where the electrode pads are formed.

Nakata et al ('834) disclose a probe sheet with probe terminals is electrically connected to their corresponding IC terminals, an insulating substrate or a wiring board is provided on the probe sheet and an elastic member or reinforcing member is interposed between the probe sheet and the insulating substrate (see abstract).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Emily Y Chan whose telephone number is 5712721956. The examiner can normally be reached on 8:30-5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Cuneo Kammie can be reached on 5712721957. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Application/Control Number: 10/670,377

Art Unit: 2829

Page 4

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Ec 6-12-04